

**Search Notes**

Application/Control No.

10/765,311

Examiner

Hiep Nguyen

Applicant(s)/Patent under  
Reexamination

WENDELL ET AL.

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
PG PUB search		02-04-06	ASZ

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attachment	02.04.06	AN